

# LATW2012



13th IEEE Latin American Test Workshop  
April 10th-13th, 2012 Quito, Ecuador



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#### CALL FOR PAPERS

The IEEE Latin-American Test Workshop (LATW) provides an annual forum for test and fault tolerance professionals and technologists from all over the world and in particular from Latin America, to present and discuss various aspects of system, board, and component testing and fault-tolerance with design, manufacturing and field considerations in mind. Presented papers will be also published in the IEEE Xplore Digital Library. The best papers of the 13th IEEE LATW will be invited to re-submit to the IEEE Design and Test of Computers, Journal of Electronic Testing: Theory and Applications (JETTA), and Journal of Low Power Electronics (JOLPE).

#### Topics of interest include but are not limited to:

- Analog Mixed Signal Test
- Automatic Test Generation
- Built-In Self-Test
- Defect-Based Test
- Design and Synthesis for Testability
- Design for Electromagnetic Compatibility
- Design for Reliable Embedded Software
- Design Verification/Validation
- Economics of Test
- Fault Analysis and Diagnosis
- Fault Modeling and Simulation
- Fault-Tolerance in HW/SW
- Fault-Tolerant Architectures
- Memory Test and Repair
- On-Line Testing
- Process Control and Measurements
- Radiation/EMI
- Hardening Techniques
- Software Fault-Tolerance
- Software On-Line Testing
- System-on-Chip Test
- Test Resource Partitioning
- Yield Optimization

#### Paper Submission Information:

To encourage and facilitate discussions, participation will be limited. Those interested in presenting recent results at the workshop are invited to submit an extended abstract, one to three pages long, or a full length paper. PDF electronic submissions should be done via the workshop webpage: [www.latw.ttc-events.org](http://www.latw.ttc-events.org)

Authors should send papers in the IEEE format. Detailed instructions are available at the workshop webpage. The Program Committee also welcomes proposals for panels and special topic sessions.

For additional information, please contact one of the Program Chairs:

Raoul Velazco, TIMA, France: [raoul.velazco@imag.fr](mailto:raoul.velazco@imag.fr)

Leticia Maria Bolzani Pöhls, Catholic University of Rio Grande do Sul: [leticia@poehls.com](mailto:leticia@poehls.com)

**Submission Deadline:** November 7th, 2011

**Notification of Acceptance:** December 12th, 2011

**Camera Ready:** January 10th, 2012.

LATW2012 will be held in the capital of Ecuador, Quito, a colonial and contemporary city that has been declared Cultural Heritage of the Humanity. Quito offers an amazing landscape surrounded by snowy mountains and volcanoes. There you will find colors, friendship, pleasure and a great diversity of customs and traditions. Close to Quito (100Kms away) there is Otavalo, a touristic city known as an important ancient culture site engraved in the mountains, with fancy dressing, common language (Quechua) and archaeological places. In Ecuador you can find subtropical rain forest and the astonishing Galapagos Islands. This is an extraordinary natural laboratory that is a fusion of particular species of fauna and flora of unique natural value in the world.

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